


<b>Search Notes</b>  	<b>Application/Control No.</b>  10525737	<b>Applicant(s)/Patent Under Reexamination</b>  SUEHIRO, NAOKI
	<b>Examiner</b>  Flores, Leon	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with SPE David Payne in regards to the patentability of the claims.	11/13/2007	LF
Searched in NPL (IEEE).	11/1/2007	LF
Checked for possible double patenting.	11/1/2007	LF
Consulted with SPE David Payne in regards to the new rejection.	8/27/2008	LF
Consulted with SPE David Payne in regards to the arguments.	2/13/2009	LF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/L. F./ Examiner.Art Unit 2611	
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